

Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,838 Examiner	CHANG ET AL. Art Unit
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SEARCHED						
Class	Subclass	bclass Date Examin				
29	603.07 603.12 603.15 603.16	3/31/2006	ADT			
	603.18					
	603.11					
	603.13					
	DIG 16					
360	320					
	324 324.1					
	324.11	V	V			

INTERFERENCE SEARCHED				
Subclass	Date Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Text Search: NPL - IEEE Xplore Database (see search history printout)	4/1/2006	ADT		
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